Application/Control No.	Applicant(s)/Patent under Reexamination	
09/903,521	NAKAMURA, SATOSHI	
Examiner	Art Unit	
Nhan T. Tran	2615	

Nhan T. Tran

SEARCHED				
Class	Subclass	Date	Examiner	
		1		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	search - see ory printout	1/17/2006	NT	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	11/28/2005	NT
348/251-256 (text search - see search history printout)	1/17/2006	NT
358/448, 461, 515-523 (text search - see search history printout)	1/17/2006	NT
382/167, 266-275 (text search - see search history printout)	1/17/2006	NT
LIN YE	1/17/2006	NT
TUAN HO	1/17/2006	NT